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Thin films of ZnO and ZnMnO by atomic layer epitaxy

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Keywords

ZnO, magnetism, low temperature growth, organic precursors

Abstract

We discuss properties of thin films of ZnO and ZnMnO grown with atomic layer epitaxy using new, organic zinc and manganese precursors. Several characterization techniques, including X-ray diffraction, atomic force microscopy, scanning electron microscopy, cathodoluminescence, superconducting quantum interference device (SQUID) and electron spin resonance, show good topography of the films and their advantageous optical and magnetic properties.



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